## Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
10578857	SAKROWSKI, KLAUS DIETER
Examiner	Art Unit
JAEYUN LEE	1791

SEARCHED			
Class	Subclass	Date	Examiner
114	357, 361, and 67R	1/11/2010	/JL/

SEARCH NOTES			
Search Notes	Date	Examiner	
East Search (US-PGPUB, USPAT, USOCR, FPRS, EPO, JPO, Derwent,	1/25/2010	/JL/	
and IBM_TDB) and text search			
Inventor Search (EDAN)	1/11/2010	/JL/	
Consulted Primary Examiner Jeff Aftergut	1/19/2010	/J:/	

INTERFERENCE SEARCH			
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